



FPD Materials & Components Japan TC Chapter Meeting Summary and Minutes

SEMI Japan Standards Winter 2015 Meetings

February 6, 2015, 15:00-17:00

SEMI Japan, Tokyo, Japan

Next Committee Meeting

SEMI Japan Standards Spring 2015 Meetings

Friday, April 10, 2015, 14:00-17:00

SEMI Japan, Tokyo, Japan

Table 1 Meeting Attendees

Co-Chairs of FPD M&C Committee: Tadahiro Furukawa (Yamagata University), Yoshi Shibahara (Fujifilm)

SEMI Staff: Naoko Tejima (SEMI Japan)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Nishimatsuya Chain	Aruga	Hisashi	Corning International	Okamura	Haruo
Yamagata University	Furukawa	Tadahiro	Fujifilm	Shibahara	Yoshi
Teijin	Itoh	Haruhiko	SK Electronics	Shiojiri	Kazuya
Nitto Denko	Kobayashi	Shigeo	Japan Display	Watanabe	Ryoichi
Meiji University	Nagai	Kazukiyo	SEMI Japan	Tejima	Naoko

* alphabetical order by last name

Table 2 Leadership Changes

None.

Table 3 Ballot Results

Passed ballots and line items will be forwarded to the ISC Audit & Review Subcommittee for procedural review.

Failed ballots and line items were returned to the originating task forces for re-work and re-balloting.

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
5796	Reapproval of SEMI D20-0706 Terminology for FPD Mask Defect	Passed as ballotted
5797	Reapproval of SEMI D21-0706 Terminology for FPD Mask Pattern Accuracy	Passed as ballotted
5798	Reapproval of SEMI D42-0308 Specification for Ultra Large Size Mask Substrate Case	Passed as ballotted
5799	Reapproval of SEMI D53-0308 Specification for Liquid Crystal Display (LCD) Pellicles	Passed as ballotted

Table 4 Authorized Ballots

None.

Table 5 Authorized Activities

None.

Table 6 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPD M&C 150206-01	SEMI Staff	To correct start time of the next FPD Metrology Japan TC Chapter meeting to <u>14:00</u> of the previous meeting minutes.
FPD M&C 150206-02	SEMI Staff	To correct FPD M&C 140418-01 in Table 7 Previous Meeting Action Items to “ <u>to contact Backlight Task Force co-leaders</u> ” of the previous meeting minutes..
FPD M&C 150206-03	SEMI Staff	To forward adjudication result of Doc.#5796 to the ISC A&R Subcommittee for procedural review.
FPD M&C 150206-04	SEMI Staff	To forward adjudication result of Doc.#5797 to the ISC A&R Subcommittee for procedural review.
FPD M&C 150206-05	SEMI Staff	To forward adjudication result of Doc.#5798 to the ISC A&R Subcommittee for procedural review.
FPD M&C 150206-06	SEMI Staff	To forward adjudication result of Doc.#5799 to the ISC A&R Subcommittee for procedural review.
FPD M&C 150206-07	Polarizing Film Task Force	To send the revised SNRAF of Doc. #5555 to SEMI until March 15 for 2 weeks review by TC Members. <i>*Since after the committee meeting, it was turned out that 2 weeks review by TC members does not need for revised SNRAF, TF will present it at the next committee meeting.</i>
FPD M&C 150206-08	SEMI Staff	To send the revised SNRAF of Doc. #5555 to Global TC Members to review for 2 weeks. <i>*Since after the committee meeting, it was turned out that 2 weeks review by TC members does not need for revised SNRAF.</i>

1 Welcome, Reminders, and Introductions

Tadahiro Furukawa, committee co-chair, called the meeting to order at 15:00. Self-introductions were made followed by the agenda review.

2 Required Meeting Elements

The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed by SEMI staff, Naoko Tejima.

3 Review of Previous Meeting Minutes

The committee reviewed the minutes of the previous meeting held on February 6, 2015.

It was pointed the following 2 items should be changed.

- Start time of the next FPD Metrology Japan TC Chapter meeting should be corrected to 14:00.
- “To contact co-leaders” of FPD M&C 140418-01 in Table 7 Previous Meeting Action Items should be corrected to “To contact Backlight Task Force co-leaders”.

Motion: To approve the minutes of the previous meeting as written after the above points are corrected.

By / 2nd: Yoshi Shibahara (Fujifilm) / Ryoichi Watanabe (Japan Display)

Discussion: None

Vote: 6 in favor and 0 opposed. **Motion passed.**

Action Item: SEMI staff to correct start time of the next FPD Metrology Japan TC Chapter meeting to 14:00 of the previous meeting minutes.

Action Item: SEMI staff to correct FPD M&C 140418-01 in Table 7 Previous Meeting Action Items to “To contact Backlight Task Force co-leaders”.

Attachment: 01_JA_FPD_M&C_&_Metrology_Previous_Mtg_Minutes_150206

4 SEMI Staff Report

Naoko Tejima gave the SEMI staff report. This report included SEMI Global 2015 Calendar of Events, Global Standards Meeting Schedule, Report of SEMICON Japan 2014, Standards Awards 2014, 2015 Critical Dates for SEMI Standards Ballots, New Regulations and Procedure guide effective December 2014, SEMI Standards Publication, A&R Ballot Review and Contact Information.

Attachment: 02_SEMI_Staff_Report_150206

5 Liaison Reports

5.1 Korea FPD Committee Report

Naoko Tejima reported for the Korea FPD Metrology Committee. This report included Leadership, Organization Chart, Meeting Information, Major Updates, Subcommittee/TF/WG Updates and Contact Information.

Attachment: 03_KR_FPD_Liaison_Report_150206

5.2 Taiwan FPD Committee Report

Naoko Tejima reported for the Taiwan FPD Committee. This report included Leadership, FPD Standard Committee Organization Chart, FPD Standard Committee Highlights, FPD Committee Meeting Information and Contact Information.

Attachment: 04_TW_FPD_Liaison_Report_150206

6 Ballot Review

6.1 Doc.#5796, Reapproval of SEMI D20-0706 Terminology for FPD Mask Defect.

This document passed committee review and will be forwarded to the ISC A&R SC for procedural review.

Action Item: SEMI staff to forward adjudication result of Doc.#5796 to the ISC A&R Subcommittee for procedural review.

Attachment: 05_Ballot_Report_for_5796_150206

6.2 Doc.#5797, Reapproval of SEMI D21-0706 Terminology for FPD Mask Pattern Accuracy.

This document passed committee review and will be forwarded to the ISC A&R SC for procedural review.

Action Item: SEMI staff to forward adjudication result of Doc.#5797 to the ISC A&R Subcommittee for procedural review.

Attachment: 06_Ballot_Report_for_5797_150206

6.3 Doc.#5798, Reapproval of SEMI D42-0308 Specification for Ultra Large Size Mask Substrate Case.

This document passed committee review and will be forwarded to the ISC A&R SC for procedural review.

Action Item: SEMI staff to forward adjudication result of Doc.#5798 to the ISC A&R Subcommittee for procedural review.

Attachment: 07_Ballot_Report_for_5798_150206

6.4 Doc.#5799, Reapproval of SEMI D53-0308 Specification for Liquid Crystal Display (LCD) Pellicles.

This document passed committee review and will be forwarded to the ISC A&R SC for procedural review.

Action Item: SEMI staff to forward adjudication result of Doc.#5799 to the ISC A&R Subcommittee for procedural review.

Attachment: 08_Ballot_Report_for_5799_150206

7 JRSC Honor Award & Technical Committee Award

JRSC Honor Award was given to the below member to appreciate his outstanding efforts and contribution for many year

- Hisashi Aruga, Nishimatsuya Chain

Technical Committee Award were given to the below member to appreciate his outstanding efforts and leadership.

- Haruhiko Itoh, Teijin

8 Task Force Reports

8.1 Polarizing Film Task Force

Shigeo Kobayashi, Nitto Denko reported for the Polarizing Film Task Force. The Task Force met earlier in the day. Of note:

- Working for Doc. #5555, Revision to SEMI D50-0707, Test Method for Surface Hardness of FPD Polarizing Film.
- Scope of SNARF of Doc. #5555 should be expanded to Materials for FPD and Touch Panels.

Action Item: Polarizing Film Task Force to send the revised SNARF of Doc. #5555 to SEMI until March 15 for 2 weeks review by TC Members.

**Since after the committee meeting, it was turned out that 2 weeks review by TC members does not need for revised SNARF, TF will present it at the next committee meeting.*

Action Item: SEMI Staff to send the revised SNARF of Doc. #5555 to Global TC Members to review for 2 weeks.

**Since after the committee meeting, it was turned out that 2 weeks review by TC members does not need for revised SNARF.*

Attachment: 09_Polarizing _Film_TF_Report_150206

8.2 Flexible Display Task Force

Haruhiko Itoh reported on progress for the Flexible Display Task Force. The Task Force met earlier in the day. Of note:

- Working for Doc. #5551, *New Standard: Test Method for Measurement of Water Vapor Transmission Rate for Plastic Films and Sheets with High Barrier Properties for Electronic Devices.*
- Making a survey regarding to stress test of Barrier Properties to Barrier films and ITO films manufacturers until March.
- Discussing about the result at the end of March.

8.3 Color Filter Task Force

Tadahiro Furukawa reported for the Color Filter Task Force that there were no particular things should be reported.

8.4 FPD Mask Task Force

Kazuya Shiojiri reported for the FPD Mask Task Force. Of note:

- Doc.#5796, *Reapproval of SEMI D20-0706 Terminology for FPD Mask Defect*, passed committee review as previously discussed. (See 7).
- Doc.#5797, *Reapproval of SEMI D21-0706 Terminology for FPD Mask Pattern Accuracy*, passed committee review as previously discussed. (See 7).
- Doc.#5798, *Reapproval of SEMI D42-0308 Specification for Ultra Large Size Mask Substrate Case*, passed committee review as previously discussed. (See 7).
- Doc.#5799, *Reapproval of SEMI D53-0308 Specification for Liquid Crystal Display (LCD) Pellicles*, passed committee review as previously discussed. (See 7).

9 Old Business

9.1 Previous Meeting Action Items

Naoko Tejima reviewed the previous meeting action items.

Table 7 Previous Meeting Actions Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPD M&C 141030-01	SEMI Staff	To correct “Meeting Attendees” and “New Action Items # FPD M&C 140418-01” of the previous meeting minutes. ... Close
FPD M&C 141030-02	SEMI Staff	To forward adjudication result of Doc.#5550 to the ISC A&R Subcommittee for procedural review. ... Close
FPD M&C 141030-03	SEMI Staff	To forward adjudication result of Doc.#5696 to the ISC A&R Subcommittee for procedural review. ... Close
FPD M&C 141030-04	SEMI Staff	To submit reapproval ballot of SEMI D20 (#5796) for Cycle 8, 2014. ... Close
FPD M&C 141030-05	SEMI Staff	To submit reapproval ballot of SEMI D21 (#5797) for Cycle 8, 2014. ... Close
FPD M&C 141030-06	SEMI Staff	To submit reapproval ballot of SEMI D42 (#5798) for Cycle 8, 2014. ... Close
FPD M&C 141030-07	SEMI Staff	To submit reapproval ballot of SEMI D53 (#5799) for Cycle 8, 2014. ... Close

10 New Business

None.

11 Action Item Review

11.1 New Action Items

Naoko Tejima reviewed the new action items. These can be found in the New Action Items table at the beginning of these minutes.

12 Next Meeting and Adjournment

The next meeting of the FPD Materials & Components Japan TC Chapter is scheduled for Friday, April 10, 2015, 14:00-17:00, SEMI Japan, Tokyo, Japan

13 Next Meeting and Adjournment

The next meeting of the FPD Materials & Components Japan TC Chapter and the FPD Metrology Japan TC Chapter Joint Meeting is scheduled for Friday, April 10, 2015, 14:00-17:00, SEMI Japan, Tokyo, Japan



Respectfully submitted by:
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Minutes approved by:

Tadahiro Furukawa (Yamagata University), Co-chair of FPD Materials & Components Japan TC Chapter	Mar. **, 2015
Yoshi Shibahara (Fujifilm) , Co-chair of FPD Materials & Components Japan TC Chapter	Mar. 12, 2015

Table 8 Index of Available Attachments #1

#	<i>Title</i>
1	JA_FPD_M&C_&_Metrology_Previous_Mtg_Minutes_150206
2	SEMI_Staff_Report_150206
3	KR_FPD_Liaison_Report_150206
4	TW_FPD_Liaison_Report_150206
5	Ballot_Report_for_5796_150206
6	Ballot_Report_for_5797_150206
7	Ballot_Report_for_5798_150206
8	Ballot_Report_for_5799_150206
9	Polarizing_Film_TF_Report_150206

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Naoko Tejima at the contact information above.